

# Jan Oliver Oelerich

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/9575740/publications.pdf>

Version: 2024-02-01

8  
papers

106  
citations

1684188  
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1588992  
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g-index

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all docs

8  
docs citations

8  
times ranked

123  
citing authors

#	ARTICLE	IF	CITATIONS
1	STEMsalabim: A high-performance computing cluster friendly code for scanning transmission electron microscopy image simulations of thin specimens. Ultramicroscopy, 2017, 177, 91-96.	1.9	50
2	Influence of surface relaxation of strained layers on atomic resolution ADF imaging. Ultramicroscopy, 2017, 181, 8-16.	1.9	17
3	Composition determination of semiconductor alloys towards atomic accuracy by HAADF-STEM. Ultramicroscopy, 2019, 200, 84-96.	1.9	15
4	Surface relaxation of strained Ga(P,As)/GaP heterostructures investigated by HAADF STEM. Journal of Microscopy, 2017, 268, 239-247.	1.8	11
5	Segregation at interfaces in (GaIn)As/Ga(AsSb)/(GaIn)As- quantum well heterostructures explored by atomic resolution STEM. Journal of Crystal Growth, 2019, 524, 125180.	1.5	7
6	Composition determination of multinary III/V semiconductors via STEM HAADF multislice simulations. Ultramicroscopy, 2018, 185, 15-20.	1.9	4
7	Ab-initio calculation of band alignments for opto-electronic simulations. AIP Advances, 2019, 9, 055328.	1.3	1
8	Half-occupation approach for the ab initio calculation of strained Ga(AsSb)/GaAs valence band offsets. AIP Advances, 2020, 10, 045207.	1.3	1